

<b>Notice of References Cited</b>	Application/Control No. 10/729,979	Applicant(s)/Patent Under Reexamination CHIN, YUAN-CHANG	
	Examiner Jinhee J. Lee	Art Unit 2174	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0142333	07-2003	Nguyen et al.	358/1.11
*	B	US-2001/0043214	11-2001	NAKATSUJI et al.	345/471
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**FOREIGN PATENT DOCUMENTS**

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